

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

#5

**INFORMATION DISCLOSURE
STATEMENT**

Docket Number:
2345/163

Application Number
To Be Assigned

Filing Date
Herewith

Examiner
To Be Assigned

Art Unit
To Be Assigned

Title
METHOD FOR MONITORING THE
TRANSMISSION QUALITY OF AN OPTICAL
TRANSMISSION SYSTEM, IN PARTICULAR OF
AN OPTICAL WAVELENGTH-DIVISION
MULTIPLEX NETWORK

Applicant(s)
Norbert HANIK et al.

Address to:
Assistant Commissioner for Patents
Washington D.C. 20231

1. In accordance with the duty of disclosure under 37 C.F.R. § 1.56 and in conformance with the procedures of 37 C.F.R. §§ 1.97 and 1.98 and M.P.E.P. § 609, attorneys for Applicant(s) hereby bring the following reference(s) to the attention of the Examiner. The reference(s) are listed on the attached modified PTO Form No. 1449. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the reference(s) be made of record therein and appear among the "References Cited" on any patent to issue therefrom.
2. A copy of each patent, publication or other information listed on the modified PTO form 1449 is enclosed, except as otherwise indicated on the modified PTO form 1449.

Dated:

8/13/2001

By:

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INFORMATION DISCLOSURE STATEMENT BY APPLICANT PTO FORM 1449	ATTY. DOCKET NO. 2345/163	SERIAL NO. Not yet assigned
	APPLICANT(s) Norbert HANIK et al.	
	FILING DATE Herewith	GROUP Not yet assigned

U. S. PATENT DOCUMENTS

EXAMINER INITIAL	PATENT NUMBER	PATENT DATE	NAME

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
				YES	NO

OTHER DOCUMENTS

EXAMINER INITIAL		AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.
		*Mueller, et al., "Application of Amplitude Histograms For Quality of Service Measurements of Optical Channels and Fault Identification," ECOC98, September 20-24, 1998, Madrid, Spain, pages 707-708.
		*Patent Abstracts of Japan, & JP 10 239214 A, vol. 1998, no. 14, September 11, 1998.
		*Shake, et al., "Optical Signal Quality Monitoring Method Based on Optical Sampling," Electronics Letters, vol. 34, no. 22, October 23, 1998, pages 2152-2154.
		*Atsushi Hiramatsu, "Training Techniques for Neural Network Applications in ATM," IEEE Service Center, New Jersey, U.S.A., vol. 33, no. 10, October 1, 1995, pages 58, 63-67.

*Copy of reference is not enclosed because reference is cited and described in International Search Report (copy of reference provided by International Searching Authority).

EXAMINER	DATE CONSIDERED
EXAMINER: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	